# High-Speed USB 2.0 (480 Mbps) DPDT Switches

ON Semiconductor's NLAS7222B and NLAS7222C are part of a series of analog switch circuits that are produced using the company's advanced sub-micron CMOS technology, achieving industry-leading performance.

Both the NLAS7222B and NLAS722C are 2- to 1-port analog switches. Their wide bandwidth and low bit-to-bit skew allow them to pass high-speed differential signals with good signal integrity. Each switch is bidirectional and offers little or no attenuation of the high-speed signals at the outputs. Industry-leading advantages include a propagation delay of less than 250 ps, resulting from its low channel resistance and low I/O capacitance. Their high channel-to-channel crosstalk rejection results in minimal noise interference. Their bandwidth is wide enough to pass High-Speed USB 2.0 differential signals (480 Mb/s).

### Features

- $R_{ON}$  is Typically 8.0  $\Omega$  at  $V_{CC}$  = 3.3 V
- Low Crosstalk: -30 dB @ 250 MHz
- Low Current Consumption: 1.0 µA
- Channel On–Capacitance: 8.0 pF (Typical)
- V<sub>CC</sub> Operating Range: 1.65 V to 4.5 V
- > 700 MHz Bandwidth (or Data Frequency)
- These are Pb-Free Devices

### **Typical Applications**

- Differential Signal Data Routing
- USB 2.0 Signal Routing

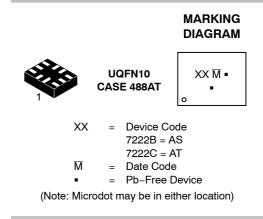
### Important Information

- Continuous Current Rating Through Each Switch ±300 mA
- 8 kV I/O to GND ESD Protection



# **ON Semiconductor®**

http://onsemi.com



### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 9 of this data sheet.

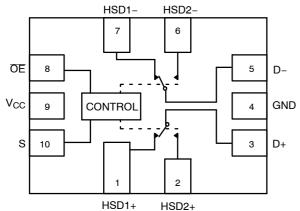


Figure 1. Pin Connections and Logic Diagram (NLAS7222B, Top View)

### **Table 1. PIN DESCRIPTION**

Pin	Function
S	Select Input
ŌĒ	Output Enable
HSD1+, HSD1-, HSD2+, HSD2-, D+, D-	Data Ports

### MAXIMUM RATINGS

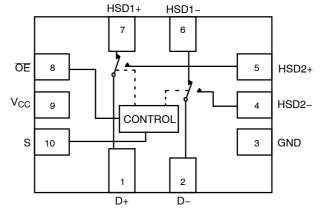


Figure 2. Pin Connections and Logic Diagram (NLAS7222C, Top View)

### Table 2. TRUTH TABLE

ŌE	s	HSD1+, HSD1-	HSD2+, HSD2-
1	X	OFF	OFF
0	0	ON	OFF
0	1	OFF	ON

Symbol	Pins	Parameter	Value	Unit
V <sub>CC</sub>	V <sub>CC</sub>	Positive DC Supply Voltage	–0.5 to +5.5	V
V <sub>IS</sub>	HSD1+, HSD1- HSD2+, HSD2-	Analog Signal Voltage	-0.5 to V <sub>CC</sub> + 0.3	V
	D+, D-		-0.5 to +5.5	
V <sub>IN</sub>	S, OE	Control Input Voltage, Output Enable Voltage	–0.5 to +5.5	V
I <sub>CC</sub>	V <sub>CC</sub>	Positive DC Supply Current	50	mA
T <sub>S</sub>		Storage Temperature	-65 to +150	°C
I <sub>IS_CON</sub>	Storage Temperature HSD1+, HSD1- HSD2+, HSD2-, D+, D-		±300	mA
I <sub>IS_PK</sub>	HSD1+, HSD1- HSD2+, HSD2-, D+, D-	Analog Signal Continuous Current 10% Duty Cycle	±500	mA
I <sub>IN</sub>	S, OE	Control Input Current, Output Enable Current	±20	mA

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Pins	Parameter	Min	Max	Unit
V <sub>CC</sub>		Positive DC Supply Voltage	1.65	4.5	V
V <sub>IS</sub>	HSD1+, HSD1- HSD2+, HSD2-	Analog Signal Voltage	GND	V <sub>CC</sub>	V
	D+, D–		GND	4.5	
V <sub>IN</sub>	S, OE	Control Input Voltage, Output Enable Voltage	GND	V <sub>CC</sub>	V
T <sub>A</sub>		Operating Temperature Range	-40	+85	°C

Minimum and maximum values are guaranteed through test or design across the Recommended Operating Conditions, where applicable. Typical values are listed for guidance only and are based on the particular conditions listed for section, where applicable. These conditions are valid for all values found in the characteristics tables unless otherwise specified in the test conditions.

### ESD PROTECTION

Symbol	Parameter	Value	Unit
ESD	Human Body Model – All Pins	2.0	kV
ESD	Human Body Model – I/O to GND	8.0	kV

# DC ELECTRICAL CHARACTERISTICS

# CONTROL INPUT, OUTPUT ENABLE (Typical: T = $25^{\circ}$ C, V<sub>CC</sub> = 3.3 V)

					–40°C to +85°C			
Symbol	Pins	Parameter	Test Conditions	V <sub>CC</sub> (V)	Min	Тур	Max	Unit
V <sub>IH</sub>	S, OE	Control Input, Output Enable HIGH Voltage (See Figure 3)		2.7 3.3 4.2	1.3 1.4 1.6	-	-	V
V <sub>IL</sub>	S, OE	Control Input, Output Enable LOW Voltage (See Figure 3)		2.7 3.3 4.2	-		0.4 0.4 0.5	V
I <sub>IN</sub>	S, OE	Control Input, Output Enable Leakage Current	$0 \le V_{IS} \le V_{CC}$	1.65 – 4.5	_	_	±1.0	μΑ

### **SUPPLY AND LEAKAGE CURRENT** (Typical: T = 25°C, V<sub>CC</sub> = 3.3 V)

					–40°C to +85°C			
Symbol	Pins	Parameter	Test Conditions	V <sub>CC</sub> (V)	Min	Тур	Max	Unit
I <sub>CC</sub>	V <sub>CC</sub>	Quiescent Supply Current	$V_{IS} = V_{CC}$ or GND; $I_{OUT} = 0 A$	1.65 – 4.5	-	-	1.0	μΑ
I <sub>CCT</sub>	V <sub>CC</sub>	Increase in I <sub>CC</sub> per Control Voltage	V <sub>IN</sub> = 2.6 V	3.6	-	-	10	μΑ
I <sub>OZ</sub>	HSD1+, HSD1- HSD2+, HSD2-	OFF State Leakage Current	$0 \leq V_{IS} \leq V_{CC}$	1.65 – 4.5	-	-	±1.0	μΑ
I <sub>OFF</sub>	D+, D-	Power OFF Leakage Current	$0 \leq V_{IS} \leq 4.5 \ V$	0	-	-	±1.0	μΑ

### HIGH SPEED ON RESISTANCE (Typical: T = $25^{\circ}$ C, V<sub>CC</sub> = 3.3 V)

					–40°C to +85°C		С	
Symbol	Pins	Parameter	Test Conditions	V <sub>CC</sub> (V)	Min	Тур	Max	Unit
R <sub>ON</sub>		On-Resistance	V <sub>IS</sub> = 0 V to 0.4 V, I <sub>ON</sub> = 8 mA	2.7 3.3 4.2	-	9.0 8.0 7.0	12 10 8.0	Ω
R <sub>FLAT</sub>		On-Resistance Flatness	V <sub>IS</sub> = 0 V to 1.0 V, I <sub>ON</sub> = 8 mA	2.7 3.3 4.2	-	1.6 1.5 1.4	-	Ω
ΔR <sub>ON</sub>		On-Resistance Matching	V <sub>IS</sub> = 0 V to 0.4 V, I <sub>ON</sub> = 8 mA	2.7 3.3 4.2	-	1.05 0.85 0.65	-	Ω

### DC ELECTRICAL CHARACTERISTICS (continued)

#### –40°C to +85°C Symbol Pins **Test Conditions** Min Max Unit Parameter Тур V<sub>CC</sub> (V) $V_{IS}$ = 0 V to V\_{CC}, $I_{ON}$ = 8 mA R<sub>ON</sub> On-Resistance 2.7 9.0 12 Ω 10.5 3.3 8.5 7.5 8.5 4.2 R<sub>FLAT</sub> $V_{IS} = 0 V$ to 1.0 V, $I_{ON} =$ 2.7 1.6 On-Resistance Ω Flatness 8 mA 3.3 1.5 4.2 1.4 On-Resistance $\Delta R_{ON}$ $V_{IS}$ = 0 V to $V_{CC},\,I_{ON}$ = 2.7 2.20 Ω 8 mA Matching 3.3 2.45 4.2 2.65

## **FULL SPEED ON RESISTANCE** (Typical: T = $25^{\circ}$ C, V<sub>CC</sub> = 3.3 V)

# **AC ELECTRICAL CHARACTERISTICS**

**TIMING/FREQUENCY** (Typical: T = 25°C,  $V_{CC}$  = 3.3 V,  $R_L$  = 50  $\Omega$ ,  $C_L$  = 5 pF, f = 1 MHz)

					–40°C to +85°C		C	
Symbol	Pins	Parameter	Test Conditions	V <sub>CC</sub> (V)	Min	Тур	Max	Unit
t <sub>ON</sub>	Closed to Open	Turn-ON Time		1.65 – 4.5	-	14	30	ns
t <sub>OFF</sub>	Open to Closed	Turn-OFF Time		1.65 – 4.5	_	10	20	ns
t <sub>BBM</sub>		Break-Before-Make Delay		1.65 – 4.5	3.0	4.4	7.0	ns
BW		-3 dB Bandwidth	C <sub>L</sub> = 5 pF	1.65 – 4.5	-	500	-	MHz
			C <sub>L</sub> = 0 pF		_	750	_	

ISOLATION (Typical: T = 25°C, V<sub>CC</sub> = 3.3 V, R<sub>L</sub> = 50  $\Omega$ , C<sub>L</sub> = 5 pF, f = 1 MHz)

					–40°C to +85°C			
Symbol	Pins	Parameter	Test Conditions	V <sub>CC</sub> (V)	Min	Тур	Мах	Unit
O <sub>IRR</sub>	Open	OFF-Isolation	f = 250 MHz	1.65 – 4.5	-	-22	-	dB
X <sub>TALK</sub>	HSD1+ to HSD1-	Non-Adjacent Channel Crosstalk	f = 250 MHz	1.65 – 4.5	-	-30	-	dB

### **NLAS7222B CAPACITANCE** (Typical: T = 25°C, V<sub>CC</sub> = 3.3 V, R<sub>L</sub> = 50 $\Omega$ , C<sub>L</sub> = 5 pF, f = 1 MHz)

				–40°C to +85°C		C	
Symbol	Pins	Parameter	Test Conditions	Min	Тур	Max	Unit
C <sub>IN</sub>	S, OE	Control Pin Input Capacitance	$V_{CC} = 0 V$	-	3.0	-	pF
C <sub>ON</sub>	D+ to HSD1+ or HSD2+	ON Capacitance	V <sub>CC</sub> = 3.3 V; <del>OE</del> = 0 V S = 0 V or 3.3 V	-	8.0	-	pF
C <sub>OFF</sub>	HSD1n or HSD2n	OFF Capacitance	$V_{CC} = V_{IS} = 3.3 \text{ V}; \ \overline{OE} = 0 \text{ V}$ S = 3.3 V or 0 V	-	4.5	-	pF

				–40°C to +85°C		C	
Symbol	Pins	Parameter	Test Conditions	Min	Тур	Мах	Unit
C <sub>IN</sub>	S, <del>OE</del>	Control Pin, Output Enable In- put Capacitance	V <sub>CC</sub> = 0 V	-	3.0	-	pF
C <sub>ON</sub>	D+ to HSD1+ or HSD2+	ON Capacitance	V <sub>CC</sub> = 3.3 V;	-	10	-	pF
C <sub>OFF</sub>	HSD1n or HSD2n	OFF Capacitance		-	5.5	-	pF

# **NLAS7222C CAPACITANCE** (Typical: T = 25°C, V<sub>CC</sub> = 3.3 V, R<sub>L</sub> = 50 $\Omega$ , C<sub>L</sub> = 5 pF, f = 1 MHz)

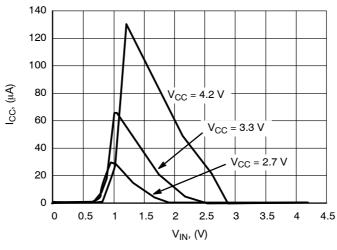


Figure 3.  $I_{CC}$  vs.  $V_{IN}$ 

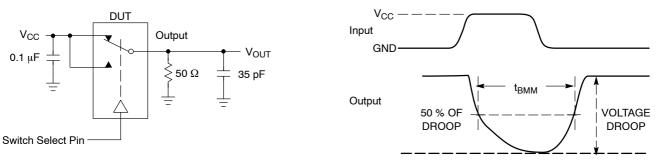
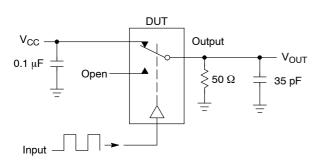


Figure 4. t<sub>BBM</sub> (Time Break-Before-Make)



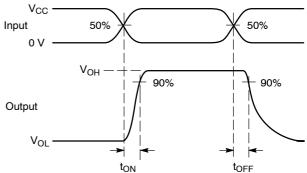
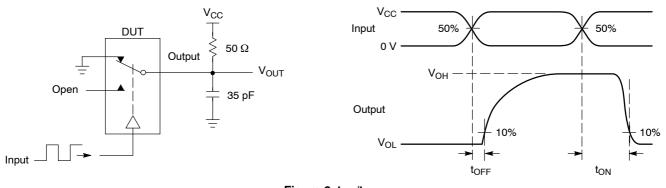
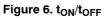
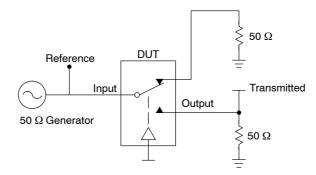


Figure 5. t<sub>ON</sub>/t<sub>OFF</sub>







Channel switch control/s test socket is normalized. Off isolation is measured across an off channel. On loss is the bandwidth of an On switch.  $V_{ISO}$ , Bandwidth and  $V_{ONL}$  are independent of the input signal direction.

$$\begin{split} V_{ISO} &= \text{Off Channel Isolation} = 20 \text{ Log}\left(\frac{V_{OUT}}{V_{IN}}\right) \text{ for } V_{IN} \text{ at } 100 \text{ kHz} \\ V_{ONL} &= \text{On Channel Loss} = 20 \text{ Log}\left(\frac{V_{OUT}}{V_{IN}}\right) \text{ for } V_{IN} \text{ at } 100 \text{ kHz} \text{ to } 50 \text{ MHz} \end{split}$$

Bandwidth (BW) = the frequency 3 dB below V<sub>ONL</sub> V<sub>CT</sub> = Use V<sub>ISO</sub> setup and test to all other switch analog input/outputs terminated with 50  $\Omega$ 

> Figure 7. Off Channel Isolation/On Channel Loss (BW)/Crosstalk (On Channel to Off Channel)/V<sub>ONL</sub>

### **APPLICATIONS INFORMATION**

The low on resistance and capacitance of the NLAS7222B provides for a high bandwidth analog switch suitable for applications such as USB data switching. Results for the USB 2.0 signal quality tests will be shown in this section, along with a description of the evaluation test board. The data for the eye diagram signal quality and jitter tests verifies that the NLAS7222B can be used as a data switch in low, full and high speed USB 2.0 systems.

Figures 8, 9 and 10 provide a description of the test evaluation board. The USB tests were conducted per the procedures provided by the USB Implementers Forum (www.usb.org), the industry group responsible for defining the USB certification requirements. The test patterns were generated by a PC and MATLAB software, and were inputted to the analog switch through USB connectors J1 (HSD1) or J2 (HSD2). A USB certified device was plugged into connector J4 to function as a data transceiver. The high speed and full speed tests used a flash memory device, while the low speed tests used a mouse. Test connectors J3 and J5 provide a direct connection of the USB device and were used to verify that the analog switch does not distort the data signals.

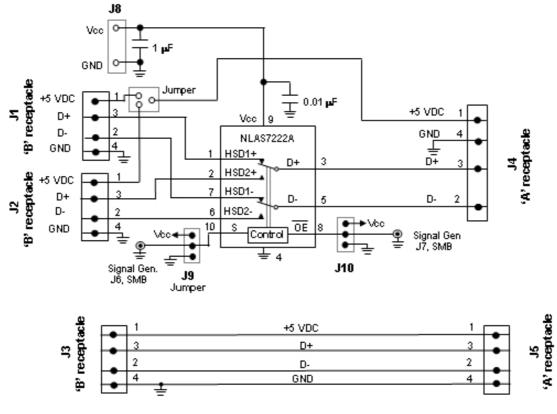


Figure 8. Schematic of the NLAS7222B USB Demo Board

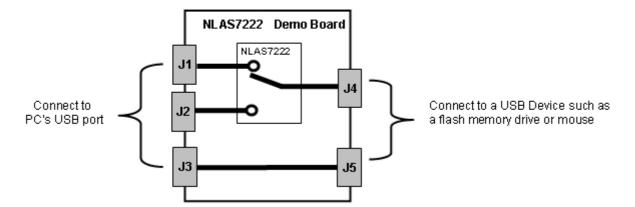


Figure 9. Block Diagram of the NLAS7222B USB Demo Board



Figure 10. Photograph of the NLAS7222B USB Demo Board

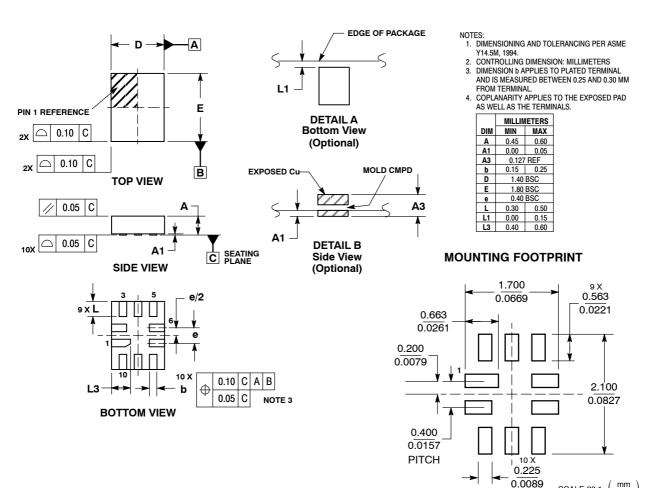
### **ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NLAS7222BMUTAG	AS	UQFN10 (Pb-Free)	3000 / Tape & Reel
NLAS7222BMUTBG	AS	UQFN10 (Pb-Free)	3000 / Tape & Reel
NLAS7222CMUTBG	AT	UQFN10 (Pb–Free)	3000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### PACKAGE DIMENSIONS

UQFN10, 1.4x1.8, 0.4P CASE 488AT-01 ISSUE A



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